

<b>PTO-1449</b>  <b>Information Disclosure Citation In an Application</b>		Application No. <del>To be Assigned</del> <b>10/725,977</b>		Applicant(s) <b>Srinivasan (nmi) Chakravarthi et al.</b>			
		Docket Number <b>TI-36386 (032350.B538)</b>		Group Art Unit <del>To be Assigned</del> <b>2822</b>			
				Filing Date <b>December 1, 2003</b>			
<b>U.S. PATENT DOCUMENTS</b>							
		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES    NO
<b>NON-PATENT DOCUMENTS</b>							
		NONPATENT DOCUMENT (Including Author, Title, Source, and Pertinent Pages)					DATE
JM1	A	Scott Thompson, "MOS Scaling: Transistor Challenges for the 21st Century – Abstract," Intel Technologies Journal, 3rd Quarter 1998, pp. 1-2					September 1998
JM1	B	Scott Thompson, "MOS Scaling: Transistor Challenges for the 21st Century – Oxide Scaling,," Intel Technologies Journal, 3rd Quarter 1998, pp. 1-9					September 1998
JM1	C	Scott Thompson, "MOS Scaling: Transistor Challenges for the 21st Century – Source Drain Engineering," Intel Technologies Journal, 3rd Quarter 1998, pp. 1-10					September 1998
JM1	D	Scott Thompson, "MOS Scaling: Transistor Challenges for the 21st Century – Channel Engineering," Intel Technologies Journal, 3rd Quarter 1998, pp. 1-11					September 1998
JM1	E	Scott Thompson, "MOS Scaling: Transistor Challenges for the 21st Century – Circuit and Device Interactions," Intel Technologies Journal, 3rd Quarter 1998, pp. 1-6					September 1998
JM1	F	Scott Thompson, "MOS Scaling: Transistor Challenges for the 21st Century – Alternate Device Options," Intel Technologies Journal, 3rd Quarter 1998, pp. 1- <del>8</del> <b>5</b>					September 1998
JM1	G	Scott Thompson, "MOS Scaling: Transistor Challenges for the 21st Century – Conclusion," Intel Technologies Journal, 3rd Quarter 1998, pp. 1					September 1998
EXAMINER				DATE CONSIDERED			
<i>T. M. Thomas</i>				<i>04-11-05</i>			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							

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